PCN Number:		2016	20160322000					PCN Date: 04/6/2016	
Title: Qualify TI Ch		Chengdu	engdu (CDAT) as an additional Assembly & Test site for select devices						
Customer Contact: PCN Manager Dept: Quality Services									
Proposed 1 st Ship Da		ate:	07/6/2016	Es	stimated Sam	ple A	vailabili	ity: Provided upon Request	
Change Typ	Change Type:								
Assemb	ly Site		Assembly	Assembly Process			Assemb	nbly Materials	
Design			Electrica	Electrical Specification			Mechan	nical Specification	
X Test Site	e		Packing/	Packing/Shipping/Labeling		╎╧┤	Test Pro	ocess	
Wafer Bump Site			Wafer Bu	Wafer Bump Material		╎╧┤	Wafer B	Sump Process	
Wafer F	Wafer Fab Site		Wafer Fa	Wafer Fab Materials			Wafer F	Fab Process	
			Part num	Part number change					
				PCN	Details				
Description	of Char	nge:			1.0. 1. 0		1 (1.1917
Assembly &	ments is Test site	for the	to announ list of devic	ce the ces show	wn below. Mate	erial c	lifference	es as fo	llows:
Assemb	ly Site	Assen	nbly Site C	Drigin	Assembly Co	untry	y Code	Asse	mbly City
TI CI	ark		QAB		PH	L		Ang	eles City
TI Che	ngdu		CDA		СН	N		C	nengdu
Material Differences:									
				•	TI Clark		TI Chen	gdu	
	Мо	unt Com	pound		TI Clark 4207768		TI Chen 42071	gdu 23	-
	Mou	unt Com	pound	•	TI Clark 4207768 4208625		TI Chen 42071 42221	igdu 23 98	
Test coverag test MQ.	Mou Mou Mo Mo	unt Com Id Comp ions, con	pound bound nditions wil	, I remai	TI Clark 4207768 4208625 n consistent wit	th cur	TI Chen 42071 42221 rrent tes	gdu 23 98 ting anc	verified with
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TEXAS INSTRUMENTS ADE IN: Malaysia 2DC: 2Q: MSL 2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/C OPT: ITEM: 39 LBL: 5A (L)T0:1750 Topside Device marking	(1P (Q (31 (4w (P) (20) (22)) SN74LS07NSR) 2000 (D) 0336 T)LOT: 3959047MLA) TKY(1T) 7523483SI2 REV: (V) 0033317) CS0: SHE (21L) CC0:USA) AS0: MLA (23L) AC0: MYS	
Assembly site code for QA	3= 1		
Assembly site code for	DA = 8		
Product Affected			
TPS22966DPUR	TPS22966DPUT	TPS22968DPUR	TPS22968DPUT

Qualification Report

TPS22966DPUR Qual at TI Chengdu Approve Date 18-Mar-2016

Product Attributes

Attributes	Qual Device: TPS22966DPUR	QBS Package Reference: BQ294504DRVR	QBS Package Reference: MSP430F5528IRGC
Assembly Site	CDAT	CDAT	UTAC
Package Family	QFN	QFN	QFN
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0
Wafer Fab Supplier	RFAB	RFAB	TSMC F11
Wafer Fab Process	LBC7	LBC7	TSMC.018 EMB FLASH

- QBS: Qual By Similarity

- Qual Device TPS22966DPUR is qualified at LEVEL2-260C

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: TPS22966DPUR	QBS Package Reference: BQ294504DRVR	QBS Package Reference: MSP430F5528IRGC
AC	Autoclave 121C	96 Hours	3/231/0	3/231/0	
FLAM	Flammability (UL 94V-0)	-	-	-	1/5/0
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0	-
HTSL	High Temp Storage Bake 170C	420 Hours	3/231/0	-	-
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	Pass	Pass	-
MSL	Thermal Path Integrity	Level 1-260C	-	3/36/0	-
MSL	Thermal Path Integrity	Level 2-260C	3/36/0	-	-
PD	Physical Dimensions	(per mechanical drawing)	3/15/0	-	-
тс	Temperature Cycle, - 65/150C	500 Cycles	3/231/0	3/231/0	-

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com